

Dual octal latch (3-State)

74F604

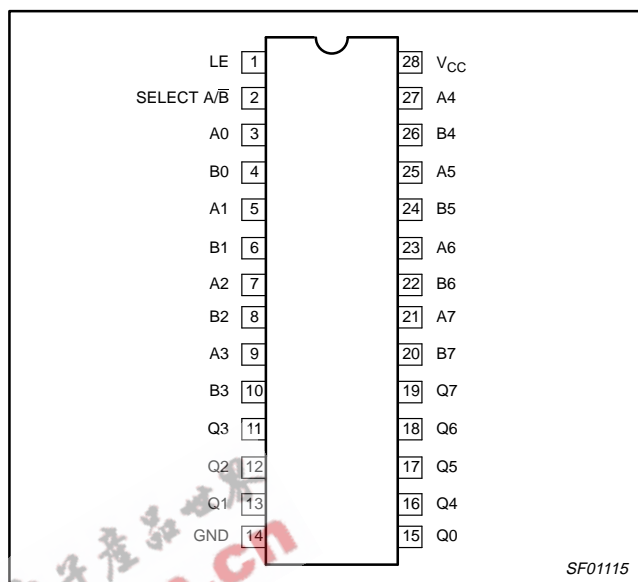
FEATURES

- High impedance NPN base inputs for reduced loading (20 μ A in High and Low states)
- Stores 16-bit-wide Data inputs, multiplexed 8-bit outputs
- 3-State outputs
- Power supply current 75mA typical

DESCRIPTION

The 74F604 multiplexed latch is ideal for storing data from two input buses, A or B, and providing data from either the A or B latches to the output bus. Organized as 8-bit A and B latches, the latch outputs are connected by pairs to eight 2-input multiplexers. A Select (SELECT A/ \bar{B}) input determines whether the A or B latch contents are multiplexed to the eight 3-State outputs. Data entered from the B inputs are selected when SELECT A/ \bar{B} is Low; data from the A inputs are selected when SELECT A/ \bar{B} is High. Data enters the latches when the Latch Enable (\bar{LE}) input is Low and is latched on the \bar{LE} rising edge. The outputs are enabled when \bar{LE} is High and disabled when \bar{LE} is Low.

PIN CONFIGURATION



TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F604	7.5ns	75mA

ORDERING INFORMATION

DESCRIPTION	COMMERCIAL RANGE
	V _{CC} = 5V \pm 10%, T _{amb} = 0°C to +70°C
28-pin plastic DIP	N74F604N
28-pin plastic SOL	N74F604D

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0–A7, B0–B7	Data inputs	1.0/0.033	20 μ A/20 μ A
SELECT A/ \bar{B}	Select input	1.0/0.033	20 μ A/20 μ A
\bar{LE}	Latch Enable input (active Low)	1.0/0.033	20 μ A/20 μ A
Q0–Q7	Data outputs	150/40	3mA/24mA

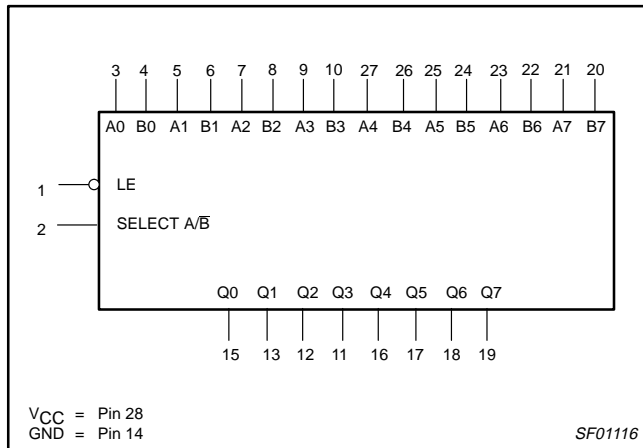
NOTE:

One (1.0) FAST unit load is defined as: 20 μ A in the High state and 0.6mA in the Low state.

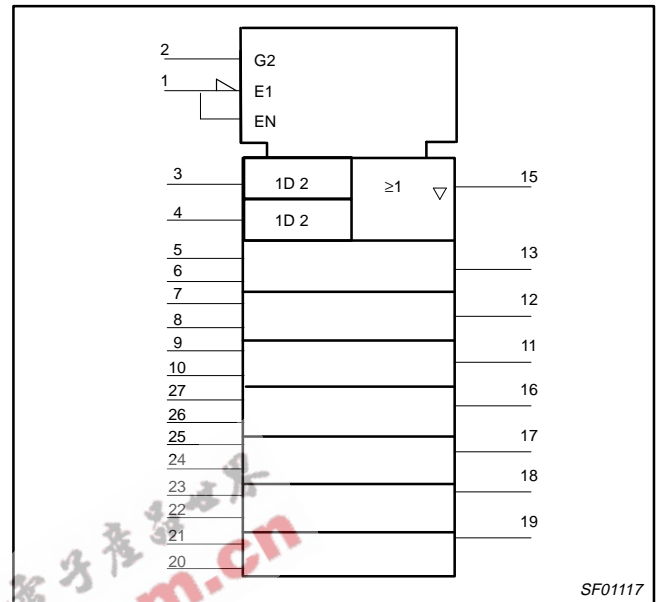
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LOGIC SYMBOL



IEC/IEEE SYMBOL (IEEE/IEC)



FUNCTION TABLE

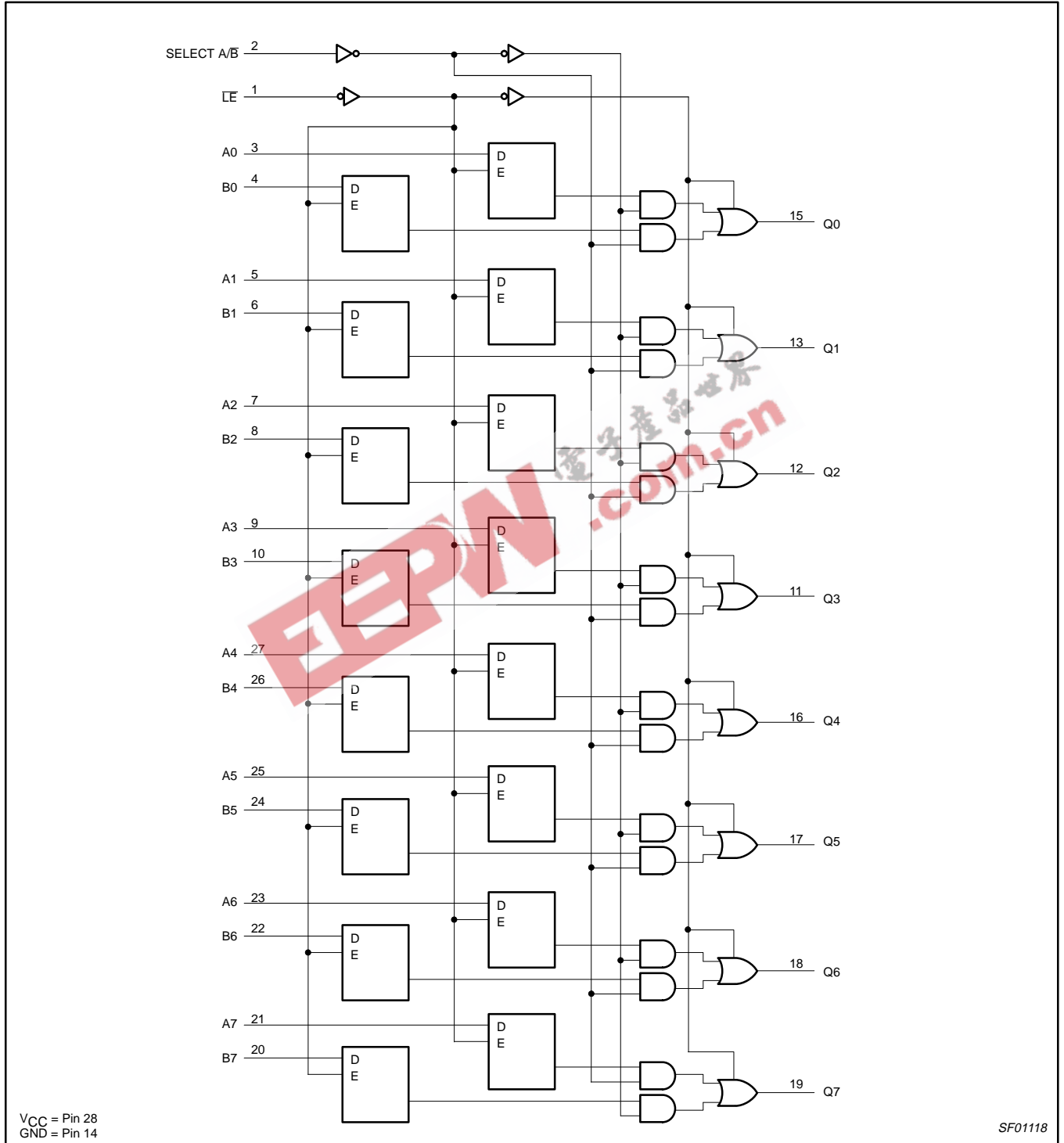
INPUTS			OUTPUTS	
A0-A7	B0-B7	SELECT A/B	LE	Q0-Q7
A data	B data	L	↑	B data
A data	B data	H	↑	B data
X	X	X	L	Z
X	X	L	H	B latched data
X	X	H	H	A latched data

- H = High voltage level
- L = Low voltage level
- X = Don't care
- Z = High impedance "off" state
- ↑ = Low-to-High clock transition

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LOGIC DIAGRAM



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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to V_{CC}	V
I_{OUT}	Current applied to output in Low output state	48	mA
T_{amb}	Operating free-air temperature range	0 to +70	°C
T_{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-3	mA
I_{OL}	Low-level output current			24	mA
T_{amb}	Operating free-air temperature range	0		70	°C

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT	
			MIN	TYP ²	MAX		
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN, I _{OH} = MAX	±10%V _{CC}	2.4		V	
			±5%V _{CC}	2.7	3.4	V	
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN, I _{OL} = MAX	±10%V _{CC}		0.35	0.50	V
			±5%V _{CC}		0.35	0.50	V
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = I _{IK}		-0.73	-1.2	V	
I _I	Input current at maximum input voltage	V _{CC} = 0.0V, V _I = 7.0V			100	μA	
I _{IH}	High-level input current	V _{CC} = MAX, V _I = 2.7V			20	μA	
I _{IL}	Low-level input current	V _{CC} = MAX, V _I = 0.5V			-20	μA	
I _{OZH}	Off state output current, High-level voltage applied	V _{CC} = MAX, V _O = 2.7V			50	μA	
I _{OZL}	Off state output current, Low-level voltage applied	V _{CC} = MAX, V _O = 0.5V			-50	μA	
I _{OS}	Short-circuit output current ³	V _{CC} = MAX	-60		-150	mA	
I _{CC}	Supply current (total)	I _{CCH}	V _{CC} = MAX	An, Bn, SELECT A/B = 4.5V, \overline{LE} = ↑	60	82	mA
		I _{CCL}		An, Bn, SELECT A/B = GND, \overline{LE} = ↑	75	100	mA
		I _{CCZ}		An, Bn, SELECT A/B = GND, \overline{LE} = GND	75	100	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
- Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			V _{CC} = +5V T _{amb} = +25°C C _L = 50pF, R _L = 500Ω			V _{CC} = +5V ± 10% T _{amb} = 0°C to +70°C C _L = 50pF, R _L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay SELECT A/B to Qn (B latch)	Waveform 1	5.0 6.0	7.0 8.5	9.0 10.5	4.5 5.5	10.0 11.5	ns
t _{PLH} t _{PHL}	Propagation delay SELECT A/B to Qn (A latch)	Waveform 2	6.0 4.0	8.0 6.5	10.0 8.5	5.5 3.5	11.5 9.0	ns
t _{PZH} t _{PZL}	Output Enable time to High or Low level	Waveform 4 Waveform 5	5.0 5.0	7.5 7.5	9.5 9.5	4.5 4.5	10.5 11.0	ns
t _{PHZ} t _{PLZ}	Output Disable time from High or Low level	Waveform 4 Waveform 5	5.0 5.0	7.0 7.0	9.5 9.5	4.5 4.5	11.0 11.0	ns

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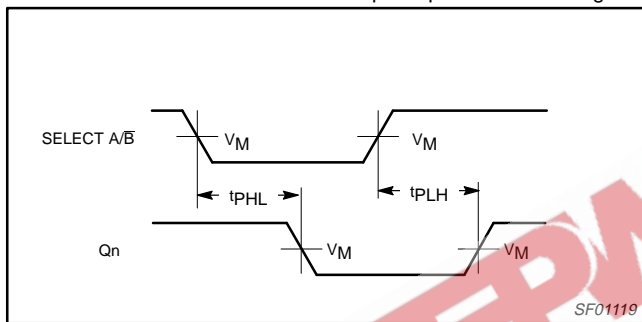
AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			V _{CC} = +5V T _{amb} = +25°C C _L = 50pF, R _L = 500Ω			V _{CC} = +5V ± 10% T _{amb} = 0°C to +70°C C _L = 50pF, R _L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	
t _s (H) t _s (L)	Setup time, High or Low An, Bn to \overline{LE}	Waveform 3	1.0 2.0			2.0 3.0		ns
t _h (H) t _h (L)	Hold time, High or Low An, Bn to \overline{LE}	Waveform 3	0 1.0			0 1.5		ns
t _W (L)	\overline{LE} Pulse width, Low	Waveform 3	5.0			6.0		ns

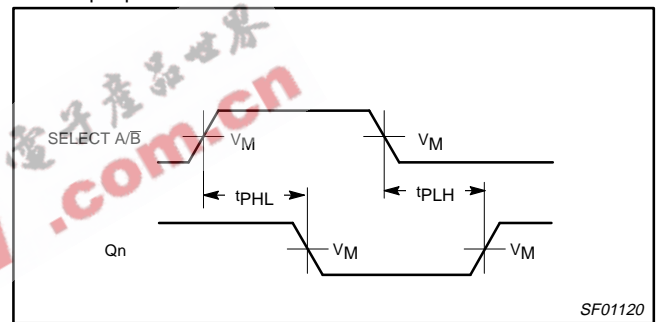
AC WAVEFORMS

For all waveforms, V_M = 1.5V.

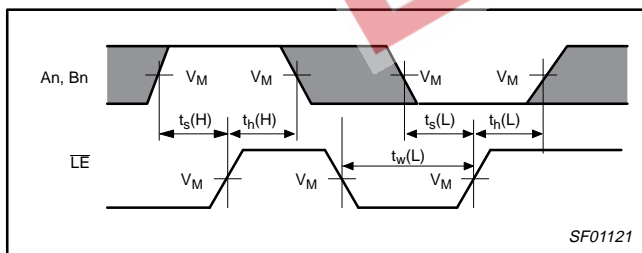
The shaded areas indicate when the input is permitted to change for predictable output performance.



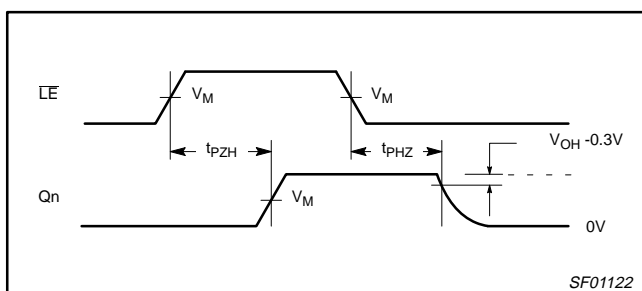
Waveform 1. Propagation Delay, SELECT A/B To Output (B latched data=Low, \overline{LE} =H)



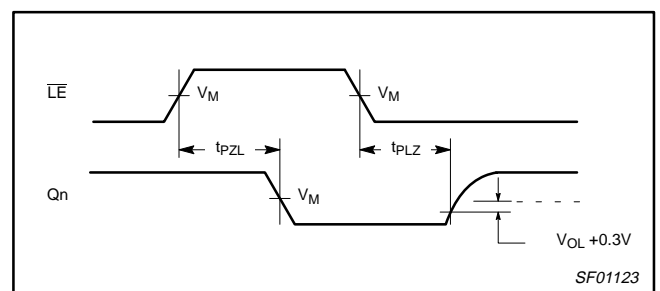
Waveform 2. Propagation Delay, SELECT A/B to Output (A latched data=Low, \overline{LE} =H)



Waveform 3. Data Setup and Hold Times, Latch Enable Pulse Width



Waveform 4. 3-State Output Enable Time to High Level and Output Disable Time from High Level



Waveform 5. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

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TEST CIRCUIT AND WAVEFORMS

Test Circuit for 3-State Outputs

SWITCH POSITION

TEST	SWITCH
t_{PLZ}	closed
t_{pZL}	closed
All other	open

DEFINITIONS:
 R_L = Load resistor; see AC electrical characteristics for value.
 C_L = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.
 R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

Input Pulse Definition

INPUT PULSE REQUIREMENTS						
family	amplitude V_M	rep. rate	t_w	t_{TLH}	t_{THL}	
74F	3.0V	1MHz	500ns	2.5ns	2.5ns	

SF00777